DS91M124 125 MHz 1:4 M-LVDS Repeater with LVCMOS Input

Check for Samples: DS91M124

FEATURES

- **DC - 125 MHz / 250 Mbps Low Jitter, Low Skew, Low Power Operation**
- **Independent Driver Enable Pins**
- **Conforms to TIA/EIA-899 M-LVDS Standard**
- **Controlled Transition Times Minimize Reflections**
- **8 kV ESD on M-LVDS I/O Pins Protects Adjoining Components**
- **Flow-Through Pinout Simplifies PCB Layout**
- **Industrial Operating Temperature Range (−40°C to +85°C)**
- **Available in a Space Saving SOIC-16 Package**

APPLICATIONS

- **Multidrop / Multipoint Clock and Data Distribution**
- **High-Speed, Low Power, Short-Reach Alternative to TIA/EIA-485/422**
- **Clock Distribution in AdvancedTCA (ATCA) and MicroTCA (µTCA) Backplanes**

DESCRIPTION

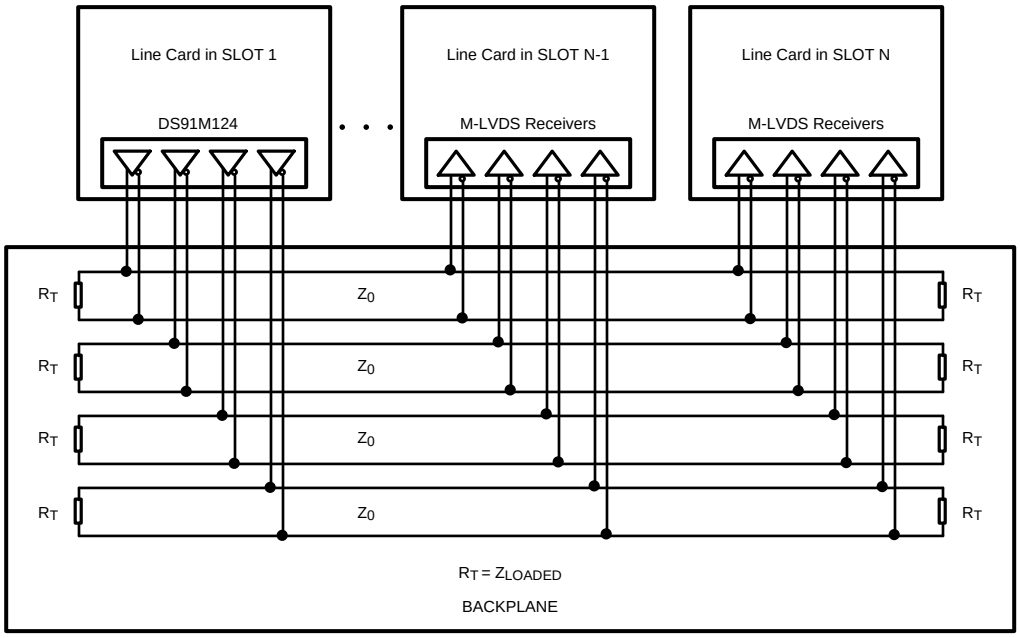
The DS91M124 is a 1:4 M-LVDS repeater for driving and distributing clock or data signals to up to four multipoint networks.

M-LVDS (Multipoint LVDS) is a new family of bus interface devices based on LVDS technology specifically designed for multipoint and multidrop cable and backplane applications. It differs from standard LVDS in providing increased drive current to handle double terminations that are required in multi-point applications. Controlled transition times minimize reflections that are common in multipoint configurations due to unterminated stubs.

A single DS91M124 channel is a 1:4 repeater that accepts LVTTL/LVCMOS signals at the driver inputs and converts them to differential M-LVDS signal levels. It features independent driver enable pins for each driver output.

The DS91M124 has a flow-through pinout for easy PCB layout. It provides a new alternative for high speed multipoint interface applications. It is packaged in a space saving SOIC-16 package.

Typical Application



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of the Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

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Pin Diagram

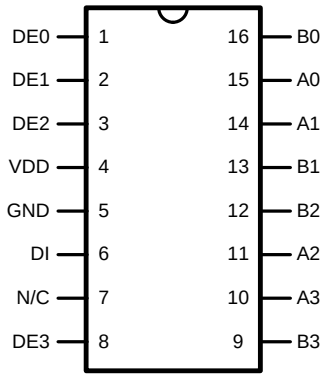
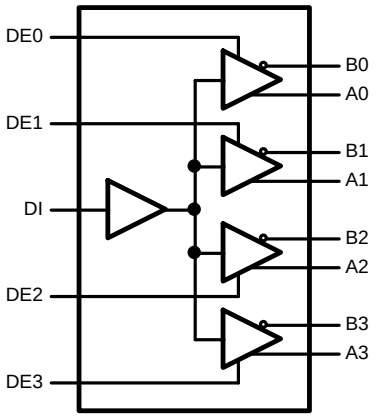


Figure 1. SOIC Package
See Package Number D0016A

Logic Diagram



Pin Descriptions

Number	Name	I/O, Type	Description
1, 2, 3, 8	DE	I, LVCMOS	Driver enable pin: When a DE pin is low, the corresponding driver output is disabled. When a DE pin is high, the corresponding driver output is enabled. There is a 300 kΩ pulldown resistor on each DE pin.
6	DI	I, LVCMOS	Driver input pin.
5	GND	Power	Ground pin.
10, 11, 14, 15	A	O, M-LVDS	Non-inverting driver output pins.
9, 12, 13, 16	B	O, M-LVDS	Inverting driver output pins.
4	V_{DD}	Power	Power supply pin, +3.3V ± 0.3V
7	N/C	N/A	NO CONNECT pin.

These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

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Absolute Maximum Ratings (1)(2)

Power Supply Voltage	−0.3V to +4V
LVCMOS Input Voltage	−0.3V to (V_{DD} + 0.3V)
M-LVDS Output Voltage	−1.9V to +5.5V
M-LVDS Output Short Circuit Current Duration	Continuous
Junction Temperature	+140°C
Storage Temperature Range	−65°C to +150°C
Lead Temperature Range	
Soldering (4 sec.)	+260°C
Maximum Package Power Dissipation @ +25°C	
D0016A Package	2.21W
Derate D0016A Package	19.2 mW/°C above +25°C
Package Thermal Resistance (4-Layer, 2 oz. Cu, JEDEC)	
θ_{JA}	+52°C/W
θ_{JC}	+19°C/W
ESD Susceptibility	
HBM (3)	≥8 kV
MM (4)	≥250V
CDM (5)	≥1250V

(1) "Absolute Maximum Ratings" indicate limits beyond which damage to the device may occur, including inoperability and degradation of device reliability and/or performance. Functional operation of the device and/or non-degradation at the Absolute Maximum Ratings or other conditions beyond those indicated in the Recommended Operating Conditions is not implied. The Recommended Operating Conditions indicate conditions at which the device is functional and the device should not be operated beyond such conditions.
(2) If Military/Aerospace specified devices are required, please contact the Texas Instruments Sales Office/ Distributors for availability and specifications.
(3) Human Body Model, applicable std. JESD22-A114C
(4) Machine Model, applicable std. JESD22-A115-A
(5) Field Induced Charge Device Model, applicable std. JESD22-C101-C

Recommended Operating Conditions

	Min	Typ	Max	Units
Supply Voltage, V_{DD}	3.0	3.3	3.6	V
Voltage at Any Bus Terminal (Separate or Common-Mode)	−1.4		+3.8	V
LVTTL Input Voltage High V_{IH}	2.0		V_{DD}	V
LVTTL Input Voltage Low V_{IL}	0		0.8	V
Operating Free Air				
Temperature T_A	−40	+25	+85	°C

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DC Electrical Characteristics

Over supply voltage and operating temperature ranges, unless otherwise specified. (1)(2)(3)(4)

Parameter		Test Conditions	Min	Typ	Max	Units
LVCMOS DC Specifications						
V_{IH}	High-Level Input Voltage		2.0		V_{DD}	V
V_{IL}	Low-Level Input Voltage		GND		0.8	V
I_{IH}	High-Level Input Current	V_{IH} = 3.6V	-15	±1	15	µA
I_{IL}	Low-Level Input Current	V_{IL} = 0V	-15	±1	15	µA
V_{CL}	Input Clamp Voltage	I_{IN} = -18 mA	-1.5			V
M-LVDS DC Specifications						
$\|V_{AB}\|$	Differential Output Voltage Magnitude	R_L = 50Ω, C_L = 5 pF Figure 2 Figure 4	480		650	mV
ΔV_{AB}	Change in Differential Output Voltage Magnitude Between Logic States		−50		50	mV
$V_{OS(SS)}$	Steady-State Common-Mode Output Voltage	Figure 2 Figure 3 R_L = 50Ω	0.30	1.6	2.10	V
$\|\Delta V_{OS(SS)}\|$	Change in Steady-State Common-Mode Output Voltage Between Logic States		0		50	mV
$V_{A(OC)}$	Maximum Steady-State Open-Circuit Output Voltage	Figure 5	0		2.4	V
$V_{B(OC)}$	Maximum Steady-State Open-Circuit Output Voltage		0		2.4	V
$V_{P(H)}$	Voltage Overshoot, Low-to-High Level Output (5)	R_L = 50Ω, C_L = 5 pF C_D = 0.5 pF Figure 7 Figure 8			$1.2V_{SS}$	V
$V_{P(L)}$	Voltage Overshoot, High-to-Low Level Output (5)		$-0.2V_{SS}$			V
I_{OS}	Output Short-Circuit Current (6)	Figure 6	-43		43	mA
I_A	Driver High-Impedance Output Current	V_A = 3.8V, V_B = 1.2V	0		32	µA
		V_A = 0V or 2.4V, V_B = 1.2V	−20		20	µA
		V_A = −1.4V, V_B = 1.2V	−32		0	µA
I_B	Driver High-Impedance Output Current	V_A = 3.8V, V_B = 1.2V	0		32	µA
		V_A = 0V or 2.4V, V_B = 1.2V	−20		20	µA
		V_A = −1.4V, V_B = 1.2V	−32		0	µA
I_{AB}	Driver High-Impedance Output Differential Curent (I_A − I_B)	V_A = V_B, −1.4V ≤ V ≤ 3.8V	−4		4	µA
$I_{A(OFF)}$	Driver High-Impedance Output Power-Off Current	V_A = 3.8V, V_B = 1.2V DE_n = 0V 0V ≤ V_{DD} ≤ 1.5V	0		32	µA
		V_A = 0V or 2.4V, V_B = 1.2V DE_n = 0V 0V ≤ V_{DD} ≤ 1.5V	−20		20	µA
		V_A = −1.4V, V_B = 1.2V DE_n = 0V 0V ≤ V_{DD} ≤ 1.5V	−32		0	µA

(1) The Electrical Characteristics tables list ensured specifications under the listed Recommended Operating Conditions except as otherwise modified or specified by the Electrical Characteristics Conditions and/or Notes. Typical specifications are estimations only and are not ensured.
(2) Current into device pins is defined as positive. Current out of device pins is defined as negative. All voltages are referenced to ground except V_{OD} and ΔV_{OD}.
(3) Typical values represent most likely parametric norms for V_{DD} = +3.3V and T_A = +25°C, and at the Recommended Operation Conditions at the time of product characterization and are not ensured.
(4) C_L includes fixture capacitance and C_D includes probe capacitance.
(5) Specification is ensured by characterization and is not tested in production.
(6) Output short circuit current (I_{OS}) is specified as magnitude only, minus sign indicates direction only.

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DC Electrical Characteristics (continued)

Over supply voltage and operating temperature ranges, unless otherwise specified. (1)(2)(3)(4)

Parameter		Test Conditions	Min	Typ	Max	Units
$I_{B(OFF)}$	Driver High-Impedance Output Power-Off Current	V_A = 3.8V, V_B = 1.2V DE_n = 0V 0V ≤ V_{DD} ≤ 1.5V	0		32	µA
		V_A = 0V or 2.4V, V_B = 1.2V DE_n = 0V 0V ≤ V_{DD} ≤ 1.5V	−20		20	µA
		V_A = −1.4V, V_B = 1.2V DE_n = 0V 0V ≤ V_{DD} ≤ 1.5V	−32		0	µA
$I_{AB(OFF)}$	Driver High-Impedance Output Power-Off Current ($I_{A(OFF)}$ − $I_{B(OFF)}$)	V_A = V_B, −1.4V ≤ V ≤ 3.8V DE_n = 0V 0V ≤ V_{DD} ≤ 1.5V	−4		4	µA
C_A	Driver Output Capacitance	V_{DD} = 0V		7.8		pF
C_B	Driver Output Capacitance			7.8		pF
C_{AB}	Driver Output Differential Capacitance			3		pF
$C_{A/B}$	Driver Output Capacitance Balance (C_A/C_B)			1		
I_{CCL}	Loaded Supply Current Enabled	R_L = 50Ω (All Outputs) DI = V_{DD} or GND DE_n = V_{DD} or GND (All Outputs)		65	75	mA
I_{CCZ}	No Load Supply Current Disabled	DI = V_{DD} or GND, DE_n = GND (All Outputs)		19	24	mA

Switching Characteristics

Over supply voltage and operating temperature ranges, unless otherwise specified. (1)(2)(3)

Parameter		Test Conditions	Min	Typ	Max	Units
t_{PHL}	Differential Propagation Delay High to Low	R_L = 50Ω C_L = 5 pF, C_D = 0.5 pF Figure 7 Figure 8	1.8	3.9	6.5	ns
t_{PLH}	Differential Propagation Delay Low to High		1.8	3.9	6.5	ns
t_{SKD1}	Differential Pulse Skew |t_{PHL} − t_{PLH}| (4) (5)		0	25	100	ps
t_{SKD2}	Channel-to-Channel Skew (4) (6)		0	70	250	ps
t_{SKD3}	Differential Part-to-Part Skew (4) (7) (Constant T_A and VDD)		0	1.5	2	ns
t_{SKD4}	Differential Part-to-Part Skew (4) (8)		0		4.7	ns
t_{TLH}	Rise Time (4)		1.1	2.0	3.0	ns
t_{THL}	Fall Time (4)		1.1	2.0	3.0	ns
t_{PHZ}	Disable Time High to Z	R_L = 50Ω C_L = 5 pF, C_D = 0.5 pF Figure 9 Figure 10		6	11	ns
t_{PLZ}	Disable Time Low to Z			6	11	ns
t_{PZH}	Enable Time Z to High			6	11	ns
t_{PZL}	Enable Time Z to Low			6	11	ns
f_{MAX}	Maximum Operating Frequency (4)		125			MHz

(1) The Electrical Characteristics tables list ensured specifications under the listed Recommended Operating Conditions except as otherwise modified or specified by the Electrical Characteristics Conditions and/or Notes. Typical specifications are estimations only and are not ensured.
(2) Typical values represent most likely parametric norms for V_{DD} = +3.3V and T_A = +25°C, and at the Recommended Operation Conditions at the time of product characterization and are not ensured.
(3) C_L includes fixture capacitance and C_D includes probe capacitance.
(4) Specification is ensured by characterization and is not tested in production.
(5) t_{SKD1}, |t_{PLHD} − t_{PHLD}|, Pulse Skew, is the magnitude difference in differential propagation delay time between the positive going edge and the negative going edge of the same channel.
(6) t_{SKD2}, Channel-to-Channel Skew, is the difference in propagation delay (t_{PLHD} or t_{PHLD}) among all output channels.
(7) t_{SKD3}, Part-to-Part Skew, is defined as the difference between the minimum and maximum differential propagation delays. This specification applies to devices at the same V_{DD} and within 5°C of each other within the operating temperature range.
(8) t_{SKD4}, Part-to-Part Skew, is the differential channel-to-channel skew of any event between devices. This specification applies to devices over recommended operating temperature and voltage ranges, and across process distribution. t_{SKD4} is defined as |Max − Min| differential propagation delay.

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Test Circuits and Waveforms

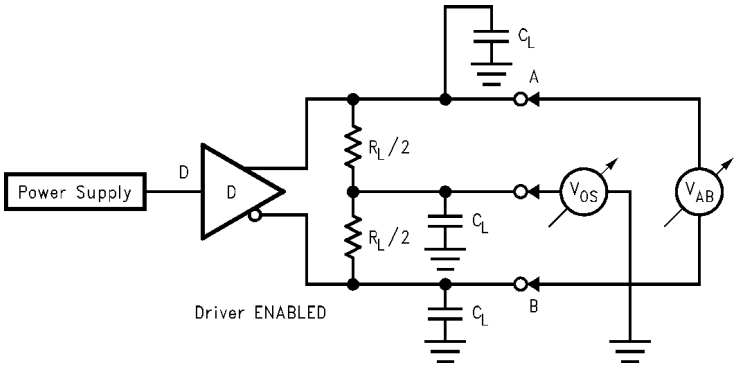


Figure 2. Differential Driver Test Circuit

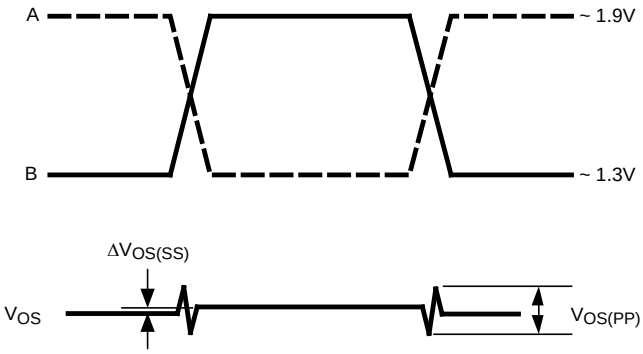


Figure 3. Differential Driver Waveforms

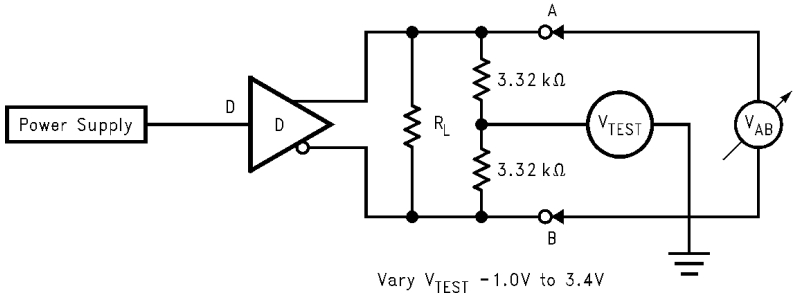


Figure 4. Differential Driver Full Load Test Circuit

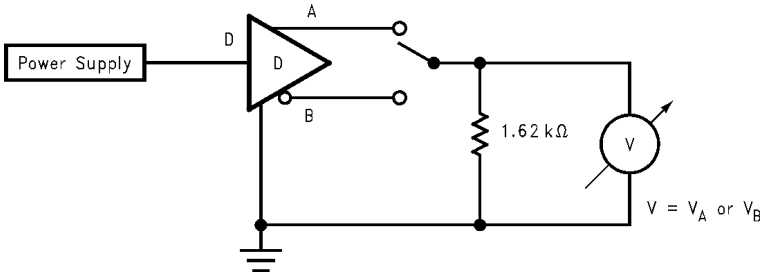


Figure 5. Differential Driver DC Open Test Circuit

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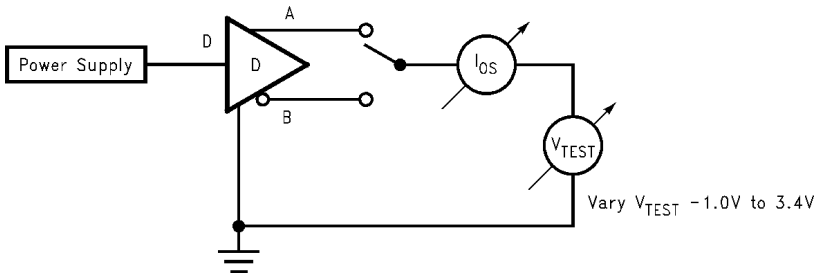


Figure 6. Differential Driver Short-Circuit Test Circuit

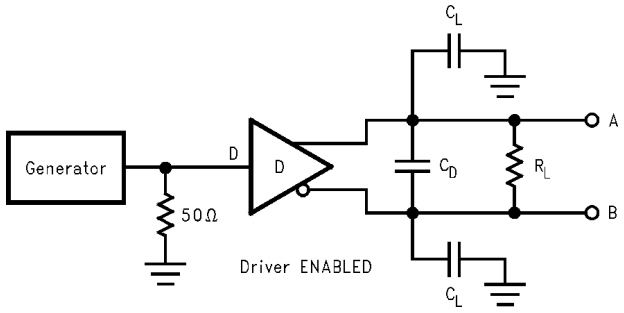


Figure 7. Driver Propagation Delay and Transition Time Test Circuit

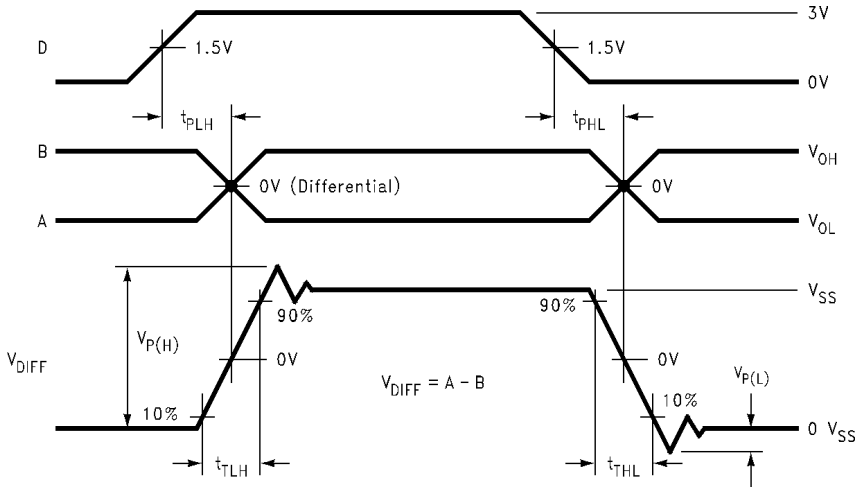


Figure 8. Driver Propagation Delays and Transition Time Waveforms

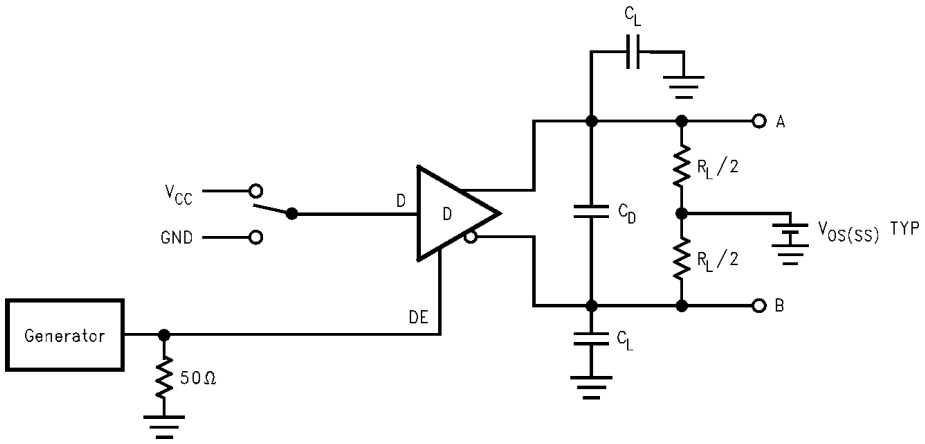


Figure 9. Driver TRI-STATE Delay Test Circuit

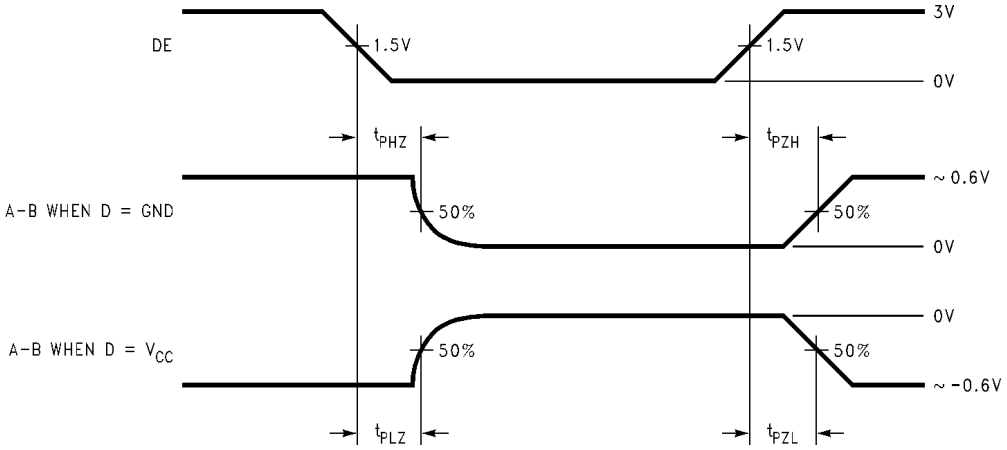


Figure 10. Driver TRI-STATE Delay Waveforms

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Typical Performance Characteristics

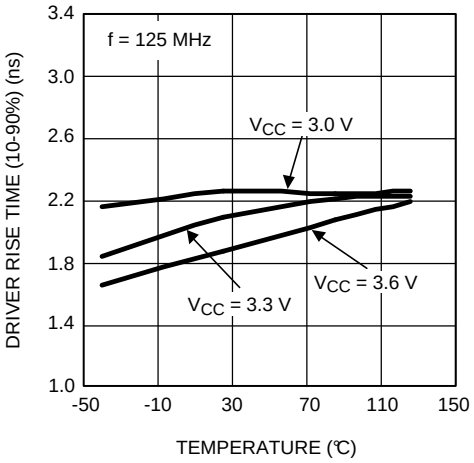


Figure 11. Driver Rise Time as a Function of Temperature

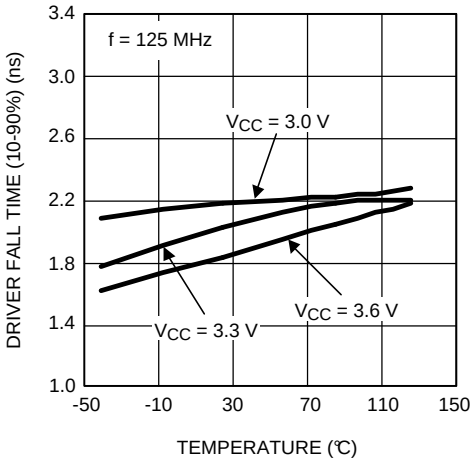


Figure 12. Driver Fall Time as a Function of Temperature

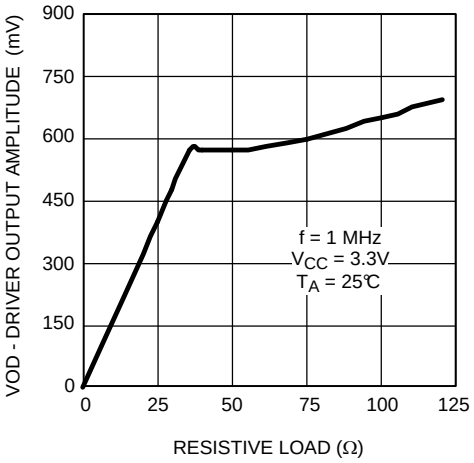


Figure 13. Driver Output Signal Amplitude as a Function of Resistive Load

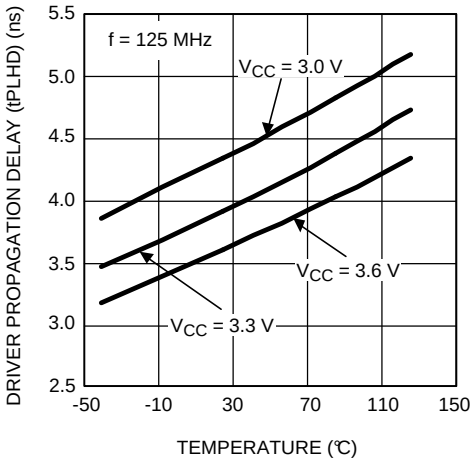


Figure 14. Driver Propagation Delay (tPLHD) as a Function of Temperature

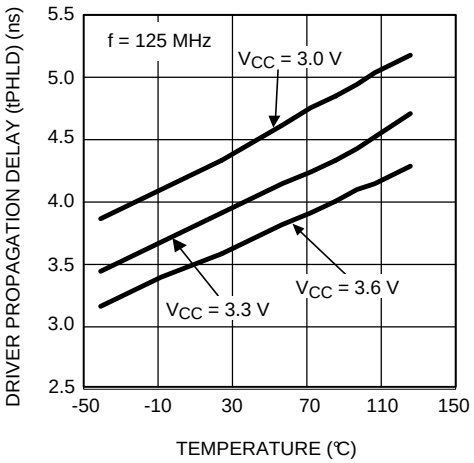


Figure 15. Driver Propagation Delay (tPHLD) as a Function of Temperature

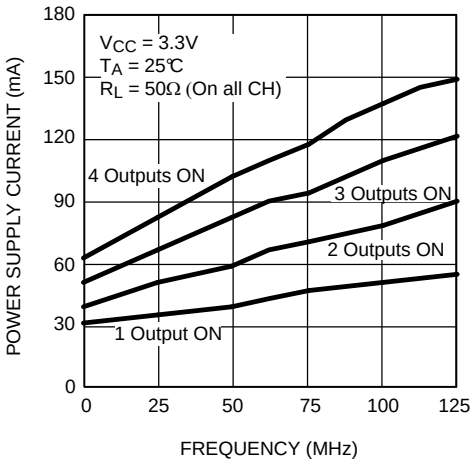


Figure 16. Driver Power Supply Current as a Function of Frequency

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REVISION HISTORY

Changes from Revision D (April 2013) to Revision E	Page
• Changed layout of National Data Sheet to TI format	9

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PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package | Pins	Package qty | Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
DS91M124TMA/NOPB	Active	Production	SOIC (D) | 16	48 | TUBE	Yes	SN	Level-1-260C-UNLIM	-40 to 85	DS91M124 TMA
DS91M124TMA/NOPB.A	Active	Production	SOIC (D) | 16	48 | TUBE	Yes	SN	Level-1-260C-UNLIM	-40 to 85	DS91M124 TMA
DS91M124TMAX/NOPB	Active	Production	SOIC (D) | 16	2500 | LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 85	DS91M124 TMA
DS91M124TMAX/NOPB.A	Active	Production	SOIC (D) | 16	2500 | LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 85	DS91M124 TMA

(1) **Status:** For more details on status, see our product life cycle.

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

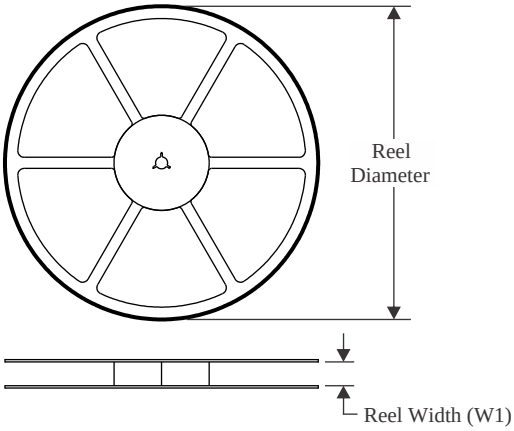
Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

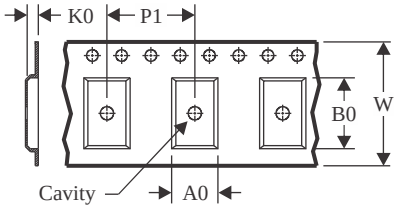
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

TAPE AND REEL INFORMATION

REEL DIMENSIONS

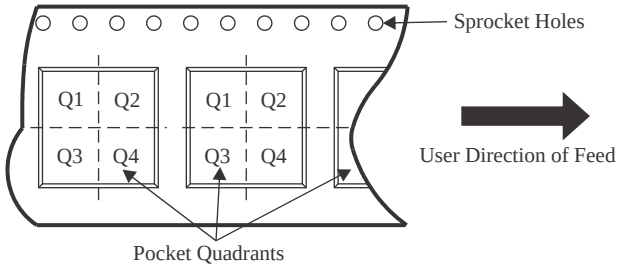


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

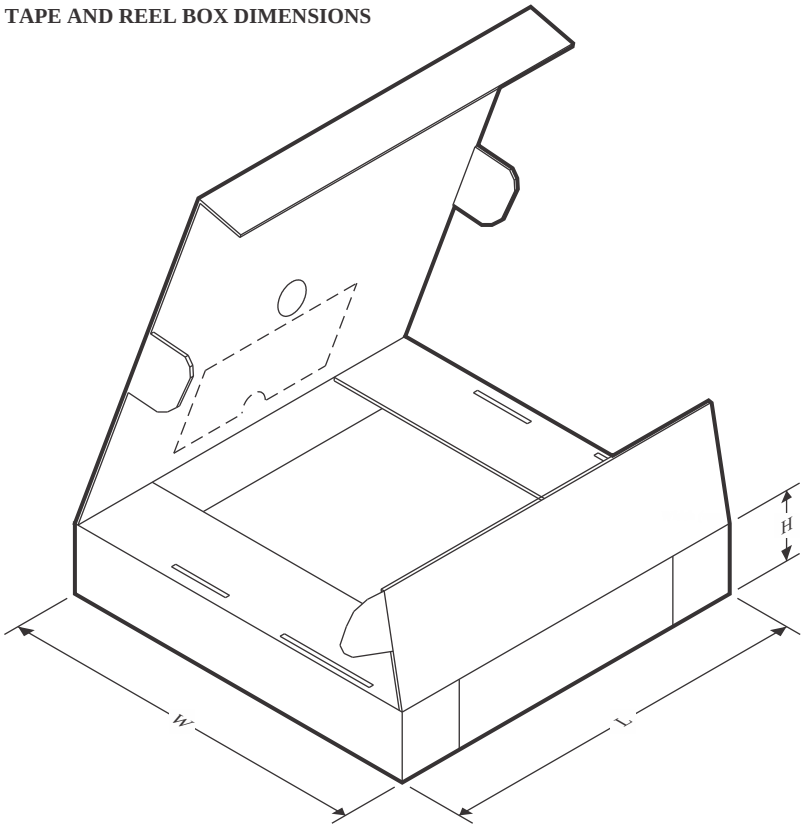
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
DS91M124TMAX/NOPB	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.3	8.0	16.0	Q1

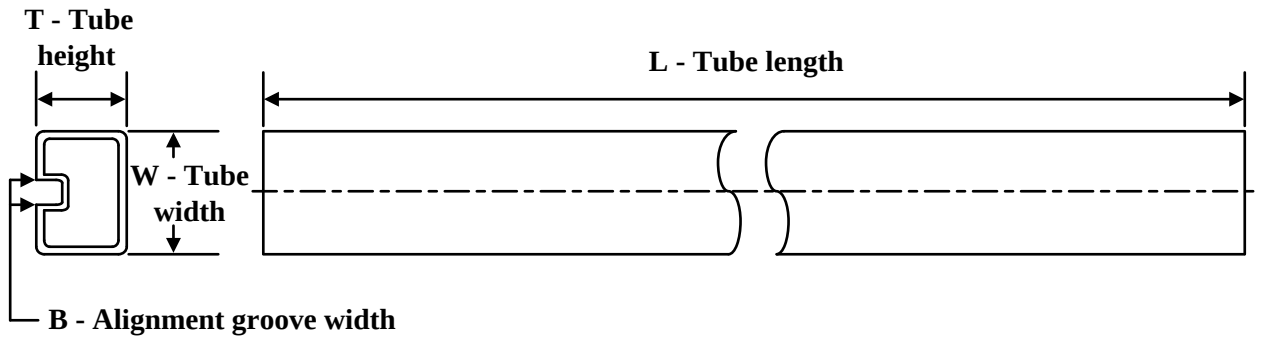
TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
DS91M124TMAX/NOPB	SOIC	D	16	2500	356.0	356.0	35.0

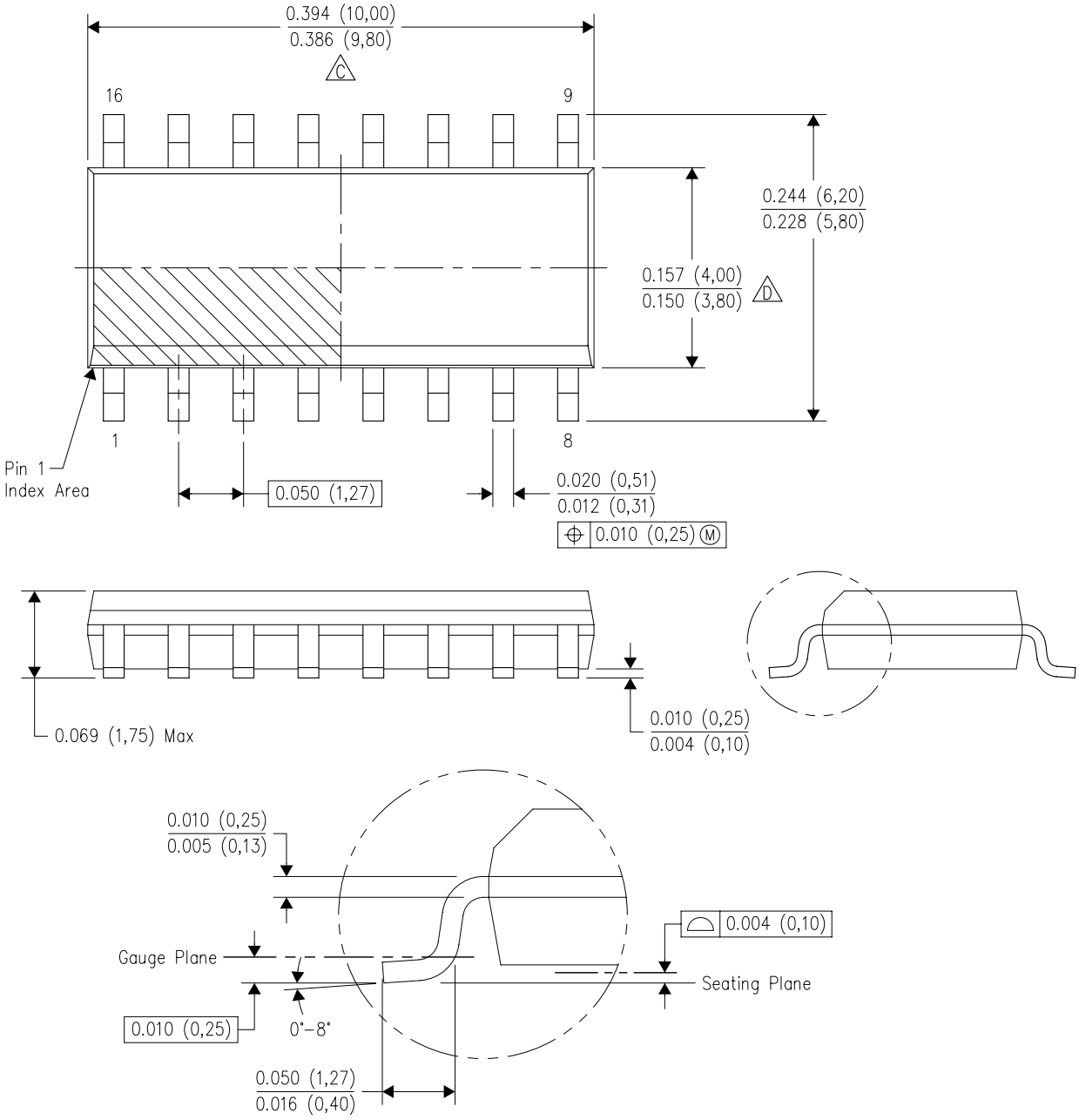
TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
DS91M124TMA/NOPB	D	SOIC	16	48	495	8	4064	3.05
DS91M124TMA/NOPB.A	D	SOIC	16	48	495	8	4064	3.05

D (R–PDSO–G16) PLASTIC SMALL OUTLINE



NOTES:
A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
D. Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
E. Reference JEDEC MS–012 variation AC.

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